Are you familiar with our industrial-grade accredited inspection services?

- Accredited laboratory in line with DIN EN ISO / IEC 17025, to qualify and validate new non-destructive testing (NDT) processes for industrial applications
- Accelerated time-to-market and opportunity for qualified, norm-compliant deployment in industrial applications as well as for new in-house developments or custom adaptation of innovative NDT technologies, even in fields where norms have not been established
- Certification of the corresponding quality management system in accordance with DIN EN ISO 9001

Air-coupled ultrasound array sensor

“Fraunhofer” and “IZFP” are registered trademarks.
Our Services

The Fraunhofer Institute for Nondestructive Testing IZFP in Saarbrücken develops and manufactures ultrasound sensors for diverse applications. The Institute has developed, among others, ultrasound sensors for the Rosetta mission, which launched on 2 March 2004 and landed on the cometary surface in November 2014.

Typically, however, we develop ultrasound sensors for material and component testing, as well as for condition monitoring over the entire product lifecycle from raw material to recycling.

Developing Ultrasound Sensor Systems

- Developing and building customer-specific ultrasound sensor systems for
  - Immersion technology
  - Contact technology
  - Air-coupled ultrasound inspection
- Test frequencies from 50 kHz to 10 MHz
- Manufacturing prototypes and smaller runs

Manufacturing 1-3 Piezocomposite Materials

- Frequencies from 200 kHz to 8 MHz
- Mechanical impedances between 8 and 13 MRayl
- Maximum dimensions up to 60 x 60 mm
- Machining to desired dimensions
- Choice of flat or focused transducers

Extended Characterization

- Characterization of the test heads according to current standards
- Visualization of the real sound field based on laser vibrometer data

Your Benefits

- High degree of reproducibility of the ultrasound sensor systems
- Short response times
- Customization to customer requirements
- Documentation for each test head